


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10689355</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>BEAUMONT, MARK</p>
	<p>Examiner</p> <p>Wai, Eric C</p>	<p>Art Unit</p> <p>2195</p>

SEARCHED			
Class	Subclass	Date	Examiner
718	105	07/20/2007	ECW
370	16	07/20/2007	ECW
395	765	07/20/2007	ECW
709	225	07/20/2007	ECW

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	07/20/2007	ECW
Inventor's Name Search	07/20/2007	ECW
Updated East Search	01/18/2008	ECW
Updated East Search for references disclosed on IDS dated 6/2/2008	8/6/2008	ECW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
718	105	8/6/2008	ECW